


<b>Search Notes</b>  	<b>Application/Control No.</b>  10597491	<b>Applicant(s)/Patent Under Reexamination</b>  SIGAI ET AL.
	<b>Examiner</b>  BRENITRA M LEE	<b>Art Unit</b>  4176

SEARCHED			
Class	Subclass	Date	Examiner
313	483-485, 487, 491, 493-494, 498, 503, 504, 506, 512, 567, 578, 634-636, 640	11/6/2008	BML

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search, Inspec, IEEE Xplore, ScieneDirect	11/6/2008	BML

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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